

Multitest MiCon® Contactor: Advantages of Cantilever Design for MCU and ASIC Testing

Significant Improvements in Overall Equipment Efficiency (OEE)

Rosenheim (Germany), July 2017: Multitest recently launched the MiCon contactor. The MiCon leverages the industry-proven Cantilever technology for the final test of Microcontrollers, Industrial DSPs and Application Specific ICs. Evaluations at customer test floors showed substantial improvements in first pass yield, life span and cleaning cycles compared to spring pin solutions. MiCon fully supports the requirements of a high, stable and reliable production output at lowest cost of test.



MiCon leverages the proven Cantilever technology for an architecture, which matches existing spring pin test boards and provides self-cleaning wipe. MiCon is a spring pin footprint compatible alternative supporting advanced temperature requirements as well as advanced power/current requirements. The footprint compatibility allows for easy and cost-efficient conversion from spring pin setups. The fully decoupled load board side of the spring ensure no degradation of the load board pad.

MiCon features a single piece design, which ensures a long lifespan, low and stable contact resistance, high current carrying capability and an extended temperature range. The MiCon allows for testing at full specification values. The extended operating range accommodates device lead trim and form variability such as device alignment accuracy and device lead coplanarity.

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Marcel Sans, Project Manager, explains: “The performance reports, received from the onsite customer evaluations, showed extraordinary advantages compared to the traditional spring pin solutions with a first pass yield of 99.8 %, time between cleaning cycles more than doubled and provided full contacting performance without signs yield degradations at high insertions counts, beyond the spring pins end of life.”

To learn more about the Multitest MiCon contactor, visit www.multitest.com/MiCon

About Multitest:

Multitest (headquartered in Rosenheim, Germany) is one of the world’s leading manufacturers of semiconductor material handling equipment and interfaces for the testing and calibration of semiconductors and sensors. Multitest markets a broad portfolio of innovative and performance driven test handlers and contactors. Multitest has more than 30 years of experience in the semiconductor industry, providing solutions to the automotive, consumer, communication, and sensor markets. Multitest is a company of Xcerra™ Corporation, which provides capital equipment, interface products, and services to the semiconductor, industrial, and electronics manufacturing industries. Xcerra Corporation offers a comprehensive portfolio of solutions and technologies, and a global network of strategically deployed applications and support resources. Additional information can be found at www.multitest.com and www.Xcerra.com

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